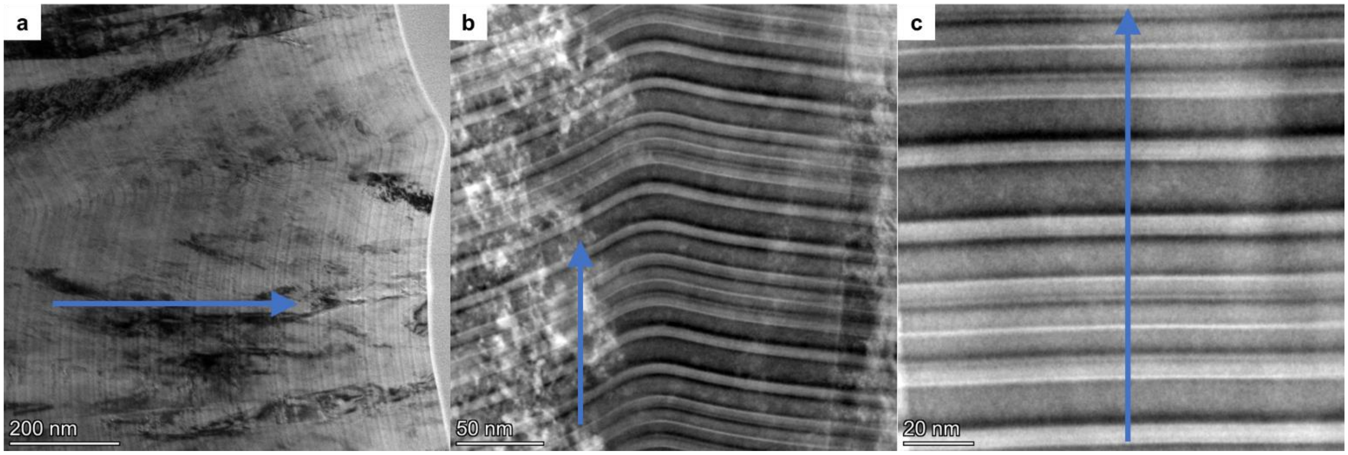
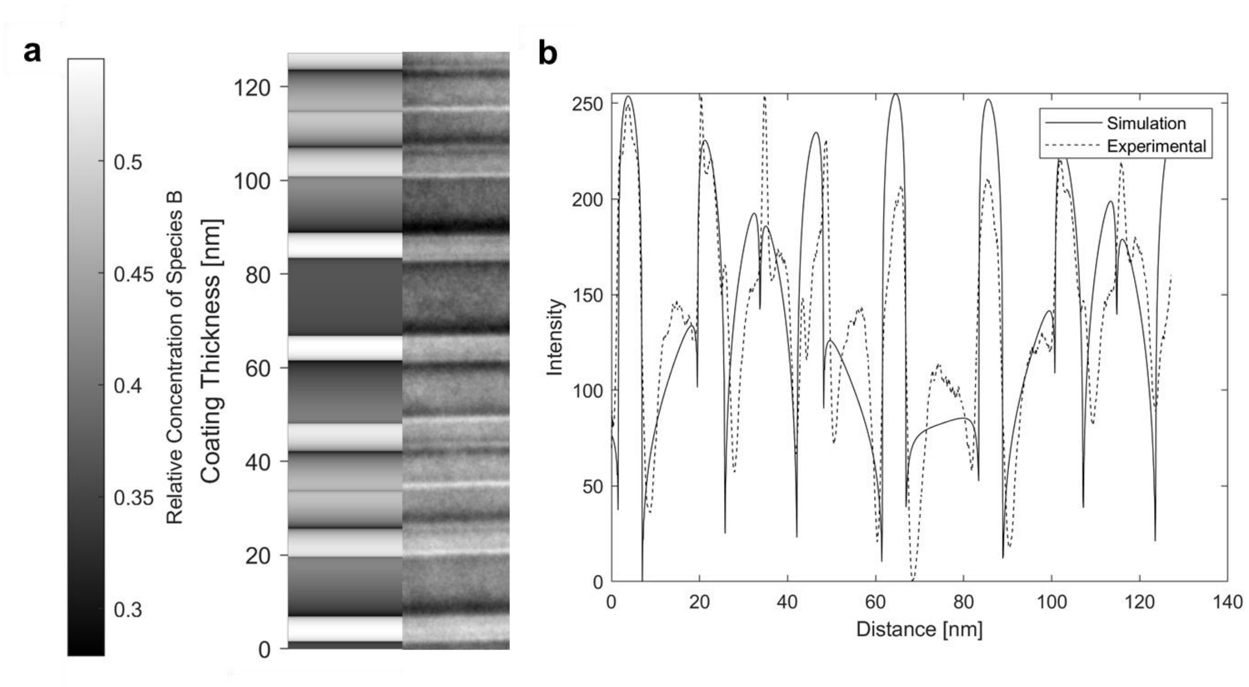


Images of FIB lamella under (a) bright field, and STEM HAADF with increasing magnification in (b) and (c). Overlayed arrows indicate the coating growth direction, and in (c) is the line used for the intensity profile.



(a) output from the simulation (left) alongside HAADF image of HEN coating (right) as an image and (b) the full-scale normalized line intensity profiles.